

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	10/632,273
Filing Date	
Inventor	
Assignee	
Group Art Unit	
Examiner	
Attorney's Docket No	
Title: Method and Apparatus for Testing Semi	conductor Circuitry for Operability and
Method of Forming Apparatus for Testing	Semiconductor Circuitry for Operability

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patent listed on the attached Form PTO-1449. No admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 10-6-05

D. Brent Kenady Reg. No. 40,045

Customer No. 021567

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

IST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO. MI22-2379

SERIAL NO. 10/632,273

APPLICANT Warren M. Farnworth

FILING DATE

July 31, 2003

GROUP 2829

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filin If App	g Date ropriate
*	AA	5,172,050	12/92	Marvin Swapp	324	999.999		
	. AB	6,686,758	02/04	Farnworth, et al.	324	765		
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^{*}EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.